REMARKS

In the foregoing amendments, claims 1, 2, 7, 10, 11, 16, 17, 19, and 22 are amended; claims 6, 9, 12-15, 18, and 21 are canceled without prejudice, disclaimer, or waiver; and claims 23-28 are added. Claims 1-5, 7, 8, 10, 11, 16, 17, 19, 20, and 22-28 are now pending in the present application.

I.   Response to 35 U.S.C. §103 Rejection

Claims 1-22 stand rejected under 35 U.S.C. §103(a) as allegedly being unpatentable over *Rajsuman et al.* (U.S. Patent No. 6,651,204) in view of *Nelson et al.* (U.S. Patent No. 6,073,264). Applicant respectfully traverses this rejection on the grounds that *Rajsuman et al.* and *Nelson et al.*, taken alone or in combination, fail to teach or suggest each and every feature of the claims, as amended.

A.   Claims 1-5, 7, 8, 10, 11, and 28

Claim 1 is an independent claim and claims 2-5, 7, 8, 10, 11, and 28 are dependent claims, which depend directly or indirectly from claim 1. Independent claim 1 is reproduced below:

1.   A method for testing a device-under-test (DUT), the method comprising:

examining a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data entries and a second plurality of data entries, the first plurality of data entries corresponding to a first plurality of DUT pins, and the second plurality of data entries corresponding to a second plurality of DUT pins;

determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins;

separating the first plurality of data entries from the second plurality of data entries;

communicating the first plurality of data entries to the first plurality of DUT pins; and

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communicating the second plurality of data entries to the second plurality of DUT pins.

(Emphasis added)

Rajsuman et al. and *Nelson et al.*, taken alone or in combination, fail to teach or suggest the above-highlighted features of claim 1. For example, claim 1 includes *determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins*. The cited references are silent regarding the aspect of *determining* whether data entries correspond to a first plurality of pins or a second plurality of pins. In particular, the references fail to teach or suggest making such a determination regarding *scan pins* and *non-scan pins*, as claimed.

In addition, claim 1 further recites *separating the first plurality of data entries from the second plurality of data entries*. The cited references appear to silent regarding this aspect regarding *separating* different data entries from each other as claimed.

For at least these reasons, it is believed that claim 1 is allowable over the cited references. Dependent claims 2-5, 7, 8, 10, 11, and 28 are believed to be allowable for at least the reason that they depend from allowable independent claim 1.

B.   Claims 16, 17, 19, and 20

Independent claim 16 is reproduced below:

16.   (Currently Amended) A system for testing a device-under-test (DUT), the system comprising:

memory operative to store a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data entries and a second plurality of data entries, the first plurality of data entries corresponding to a first plurality of DUT pins, and the second plurality of data entries corresponding to a second plurality of DUT pins; and

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a processor that is programmed to *determine whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are associated with scan pins and the second plurality of DUT pins are associated with non-scan pins*, the processor further programmed to *separate the first plurality of data entries from the second plurality of data entries*.

(Emphasis added)

Rajsuman et al. and *Nelson et al.*, taken alone or in combination, fail to teach or suggest the above-highlighted features of claim 16. For example, claim 16 includes a processor programmed to *determine whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are associated with scan pins and the second plurality of DUT pins are associated with non-scan pins*. The cited references fail to teach or suggest a processor that is programmed to *determine* whether data entries correspond to a first plurality of pins or a second plurality of pins. More particularly, the cited references fail to further disclose determining whether data entries correspond to either *scan pins* or *non-scan pins*, as claimed.

In addition, the processor claimed in claim 16 is further programmed to *separate the first plurality of data entries from the second plurality of data entries*. The cited references fail to teach or suggest a processor programmed to *separate* a first plurality of data entries from another plurality of data entries, as claimed.

For at least these reasons, it is believed that claim 16 is allowable over the combination of cited references. Also, claims 17, 19, and 20 are believed to be allowable for at least the reason that they depend, directly or indirectly, from allowable independent claim 16.

C.   Claims 22-27

Independent claim 22 is reproduced below:

22.   (Currently Amended) A system for testing a device-under-test (DUT), the system comprising:

means for storing a test data file that includes test data configured to enable testing the DUT, the test data file including a first plurality of data entries and a second plurality of data entries, the first plurality of data entries corresponding to a first plurality of DUT pins, and the second plurality of data entries corresponding to a second plurality of DUT pins;

means for determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins; and

means for separating the first plurality of data entries from the second plurality of data entries, wherein the first plurality of data entries are communicated to the first plurality of DUT pins and the second plurality of data entries are communicated to the second plurality of DUT pins.

(Emphasis added)

Rajsuman et al. and *Nelson et al.*, taken alone or in combination, fail to teach or suggest the above-highlighted features of claim 22. For example, claim 22 includes *means for determining whether each of the data entries of the test data file corresponds to a pin of the first plurality of DUT pins or to a pin of the second plurality of DUT pins, wherein the first plurality of DUT pins are scan pins and the second plurality of DUT pins are non-scan pins*. The cited references fail to teach or suggest means for *determining* whether data entries correspond to a first plurality of pins or a second plurality of pins. More particularly, the references fail to teach or suggest determining whether data entries correspond to a first or second plurality of pins, wherein the first plurality of pins are *scan pins* and the second plurality of pins are *non-scan pins*.

In addition, claim 22 further recites *means for separating the first plurality of data entries from the second plurality of data entries*. The cited references appear to be silent regarding means for *separating* a first plurality of data entries from others, as claimed.

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For at least these reasons, it is believed that claim 22 is allowable over the cited combination of references. Also, it is believed that claims 23-27 are allowable for at least the reason that they depend from allowable independent claim 22.

II.   New Claims

Claims 23-28 have been newly added to further define and/or clarify the scope of the subject matter of the present application. Claims 23-27 are dependent claims, which depend from independent claim 22. Claim 28 is a dependent claim, which depends from independent claim 1. Independent claims 1 and 22 are believed to be allowable, as discussed above, and these dependent claims are likewise believed to be allowable.
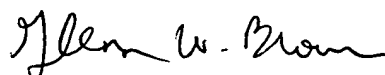
III.   References Made of Record

The references made of record have been considered, but are not believed to affect the patentability of the presently pending claims.

CONCLUSION

In light of the foregoing amendments and for at least the reasons set forth above, Applicant respectfully submits that all objections and/or rejections have been traversed, rendered moot, and/or accommodated, and that the now pending claims 1-5, 7, 7, 10, 11, 16, 17, 19, 20, and 22-28 are in condition for allowance. Any other statements in the Office Action that are not explicitly addressed herein are not intended to be admitted. Favorable reconsideration and allowance of the present application and all pending claims are hereby courteously requested. If, in the opinion of the Examiner, a telephonic conference would expedite the examination of this matter, the Examiner is invited to call the undersigned at (770) 933-9500.

Respectfully submitted,

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